

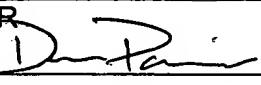
FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: P2001,0325 Appl. No.:	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Applicant: HOLGER SEDLAK ET AL.	
		Filing Date: November 4, 2003 Group Art Unit:	

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
DP	A	5,974,557	10/26/99	Thomas et al.	—	—	
DP	B	5,465,063	11/7/95	Fukuda et al.	—	—	
	C						
	D						
	E						
	F						
	G						
	H						
	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
DP	J	43 14 321 A1	2/10/94	Germany	—	—	
DP	K	41 14 363 C2	12/12/91	Germany	—	—	
DP	L	691 18 798 T2	4/1/92	Germany	—	—	
DP	M	0 477 907 B1	4/1/92	Europe	—	—	
DP	N	1 061 649 A1	12/20/00	Europe	—	—	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER 	DATE CONSIDERED 3-23-06

FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: P2001,0325					
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Appl. No.:					
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Applicant: HOLGER SEDLAK ET AL.					
		Filing Date: November 4, 2003 Group Art Unit:					

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
DP	J	10240373	9/11/98	Japan		-	
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

DP		Moore, B. D.: "Tradeoffs in Selecting IC Temperature Sensors", Microprocessors and Microsystems, Elsevier Science B. V., Vol. 23, June 3, 1999, 181-184

EXAMINER <i>Dan P.</i>	DATE CONSIDERED 3-23-06

FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: P2001,0325		Applic. No. 10/701,058	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Applicant			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Holger Sedlak et al.			
		Filing Date November 4, 2003	Group Art Unit 2836		

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	NO
DP	J	1115033 A	09/23/84	Russia				
DP	K	97119657 A	03/10/98	Russia				
DP	L	00/43860	07/27/00	WIPO				
	M							
	N							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	
	P	

EXAMINER 	DATE CONSIDERED 3-23-06
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	